

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2491		10/766376 SERIAL NO. PRIORITY <del>10/323,525</del>		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: Micron Technology, Inc.				
				FILING DATE PRIORITY December 18, 2002		GROUP PRIORITY 2824		
U.S. PATENT DOCUMENTS								
Examiner's Initials	Class	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
CDW	AA	4,704,218	11/1987	Giammarco et al.	438	421		
	AB	4,597,826	07/1986	Majima et al.	216	46		
	AC	4,648,937	03/1987	Ogura et al.	438	702		
	AD	4,857,477	08/1989	Kanamori	438	386		
	AE	4,931,137	06/1990	Sibuet	216	13		
	AF	5,618,383	04/1997	Randall	430	314		
	AG	5,795,830	08/1998	Cronin et al.	438	696		
	AH	5,895,740	04/1999	Chien et al.	430	313		
CDW	AI	6,103,596	08/2000	Peng	438	439		
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AJ							
	AK							
	AL							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AM							
	AN							
	AO							
EXAMINER		DATE CONSIDERED						
		<i>Christian Wilson</i> 8/24/04						
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

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U.S. PATENT DOCUMENTS							
Examiner's Initials	Class	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
COU	AA	6,103,613	08/2000	Akram	438	597	
f	AB	6,140,227	10/2000	Chen et al.	438	644	
f	AC	6,211,051 B1	04/2001	Jurgensen et al.	438	597	
f	AD	6,232,229 B1	05/2001	Reinberg	438	669	
f	AE	6,242,321 B1	06/2001	Acosta et al.	438	424	
SW	AF	6,509,626	01/2003	Reinberg	257	623	
	AG						
	AH						
	AI						

  

FOREIGN PATENT DOCUMENTS								
Class	Subclass	Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
		AJ						
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		AL						

  

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)		
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